

<b>Notice of References Cited</b>	Application/Control No. 10/502,140	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Christopher R. Tate	Art Unit 1655	Page 1 of 1

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*	C	US-6,593,363	07-2003	Suh et al.	514/510
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